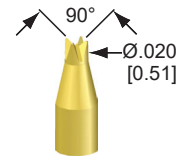
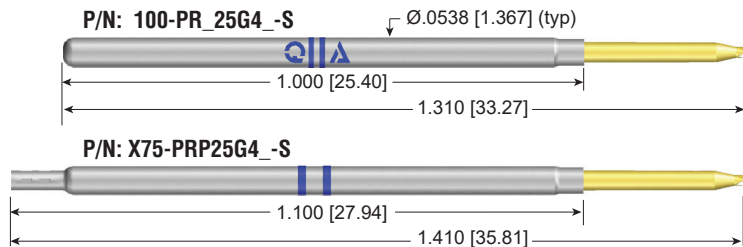


With today's complex printed circuit board processes, QA Technology continually works with customers to develop new solutions for contact challenges in their test environments.

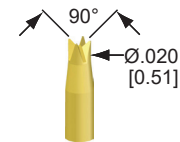
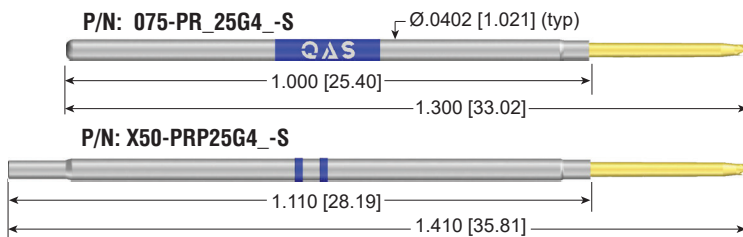
Our new "G4" Crown tip style is a self-cleaning steel tip designed with 4 sharp cutting edges to contact solder domes and test pads. In addition, the inner 90° angle feature is also beneficial in capturing small short leads. This "G4" tip has the same Ø.020 [0.51] diameter across the 100, 75 and 50mil probe series giving the advantage of the same tip geometry for a given contact feature on the Unit Under Test (UUT).

**100-25 & X75-25 Series** ~ .250 [6.35] Full Stroke, .167 [4.24] Working Stroke



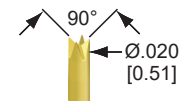
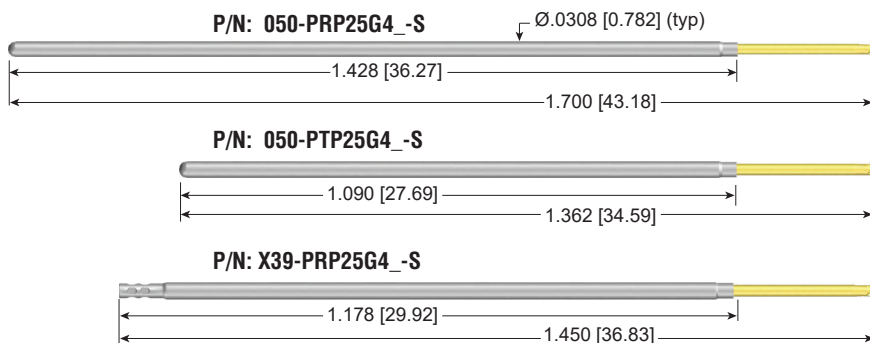
G4-s Crown

**075-25 & X50-25 Series** ~ .250 [6.35] Full Stroke, .167 [4.24] Working Stroke



G4-s Crown

**050-25 & X39-25 Series** ~ .250 [6.35] Full Stroke, .167 [4.24] Working Stroke



G4-s Crown

For more information or pricing, please contact one of Customer Service Team members at 603-926-0348 or sales@gatech.com.